

Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/603,019
		Filing Date	June 26, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Art Unit	2818
		Examiner Name	Dung-Anh LE
		Attorney Docket Number	740756-2626
Sheet	1	of	2

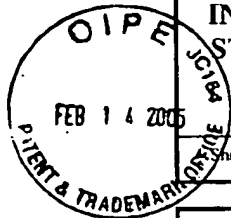
U.S. PATENT DOCUMENTS					
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
Dh		US-5,323,042 ✓	06-21-1994	MATSUMOTO	
		US-5,412,493 ✓	05-02-1995	KUNII et al.	
		US-5,528,056 ✓	06-18-1996	SHIMADA et al.	
		US-5,594,569 ✓	01-14-1997	KONUMA et al.	
		US-5,652,158 ✓	07-29-1997	BAE	
		US-5,757,444 ✓	05-26-1998	TAKEMURA	
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		US-5,953,582 ✓	09-14-1999	YUDASAKA et al.	
		US-6,013,929 ✓	01-11-2000	OHTANI	
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		US-6,693,681 B1 ✓	02-17-2004	TAKEMURA	
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		US-6,777,255 B2 ✓	08-17-2004	YAMAZAKI	

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Examiner Initials ¹	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
Dh		JP 63-222443 ✓	09-16-1988	OKABE		Abst
		JP 03-091721	04-17-1991	SAITO et al.		Abst
		JP 05-307165	11-19-1993	OZAWA		Abst
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		JP 10-012895	01-16-1998	KAWAURA et al.		Abst
Dh		JP 11-097701	04-09-1999	INOUE		Abst
		EP 0 989 614 A2	03-29-2000	YAMAZAKI et al.		

Examiner Signature	Date Considered
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¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at 222.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.



Substitute for form 1449B/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>		Application Number	10/603,019
		Filing Date	June 26, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Group Art Unit	2818
		Examiner Name	Dung-Anh LE
		Attorney Docket Number	740756-2626
Sheet	2	of	2

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
De		U.S. Application No. 09/542,473; Filed: April 4, 2000; Takayuki IKEDA et al.; ELECTROOPTICAL DEVICE AND A METHOD OF MANUFACTURING THE SAME	
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		T. YOSHIDA et al., 33.2: A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time, SID 97 Digest, pgs. 841-844.	
De		M. LEE et al., New Polycrystalline Silicon TFT's with Selectively Doped Region in The Channel, IDW '99 Proceedings of The Sixth International Display Workshops, December 1-3, 1999, pgs. 1097-1098.	

Examiner Signature	De	Date Considered	3/2005
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Substitute for Form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete If Known

Application Number	10/603,019
Filing Date	June 26, 2003
First Named Inventor	Shunpei YAMAZAKI et al.
Art Unit	2818
Examiner Name	LE, Dung-Anh
Attorney Docket Number	740756-2626

U.S. PATENT DOCUMENTS

Cite. No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patent or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Paragraphs or Relevant Figures Appear
	Number - Kind Code ² (if known)			
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	US-5,341,012	08-23-1994	MISAWA et al.	
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Examiner Initials ³	Cite. No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patent or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Paragraphs or Relevant Figures Appear	T ⁴
		Country Code ⁵ Number ⁶ Kind Code ² (if known)				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials ³	Cite. No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁴

Examiner Signature	DL	Date Considered	Sept-04
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Substitute for Form 1449A/PTO		Complete If Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	New Divisional Application
		Filing Date	June 26, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Art Unit	2815
		Examiner Name	G. Eckert, II
Sheet 1 of 2	Attorney Docket Number	740756-2626	

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Person or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
DE		US-5,182,620	01/1993	Shimada et al.	
		US-5,739,549	04/1998	Takemura et al.	
		US-5,942,310	08/1999	Moon	
		US-6,067,132	05/2000	Kim	
		US-6,137,551	10/2000	Jeong	
		US-6,271,818	08/2001	Yamazaki et al.	
		US-6,490,014	12/2002	Ohtani et al.	

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Examiner Initials	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Person or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ Number ⁴ Kind Code ² (if known)			
DE		GB 2-307 326	05/1997	Shin et al.	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS); title of the article (when appropriate); title of the item (book, magazine, journal, serial, symposium, catalog, etc.); date, page(s), volume/issue number(s), publisher, city and/or country where published.	T ⁵
DE		Shimokawa et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758.	

Examiner Signature	DE	Date Considered	4/2004
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Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket: 740756-2626	Serial No.							
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		Applicant: Shunpei YAMAZAKI et al.								
		Filing Date: June 26, 2003	Group: 2815							
U.S. PATENT DOCUMENTS										
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date				
De	5,643,826	07/01/1997	Ohtani et al.	7	2	1				
	5,923,962	07/13/1999	Ohtani et al.							
	5,895,933	04/20/1999	Zhang et al.							
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	5,608,251	03/04/1997	Konuma et al.							
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	5,712,495	01/27/1998	Suzawa							
	5,856,689	01/05/1999	Suzawa							
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	5,365,079	11/15/1994	Kodaira et al.							
	De	5,616,935	04/01/1997				Koyama et al.	7	2	1
		5,508,209	04/16/1996				Zhang et al.			
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De	07-130652	05/19/1995	Japan	7	2	Abstract				
	07-321339	12/08/1995	Japan			Abstract				
	09-312260	12/02/1997	Japan			Abstract				
	10-056184	02/24/1998	Japan			Abstract				
	10-247735	09/14/1998	Japan			Abstract				
	07-130974	05/19/1995	Japan			Abstract				
	07-135323	05/23/1995	Japan			Abstract				
	07-169974	07/04/1995	Japan			Abstract				
	07-169975	07/04/1995	Japan			Abstract				
	07-218932	08/18/1995	Japan			Abstract				
Examiner	Date Considered		4/2004							

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